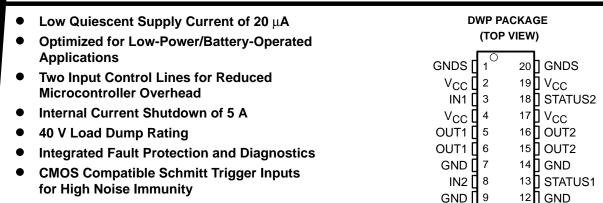
GNDS 10

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11 GNDS



description

The TPIC0108B is a PWM control intelligent H-bridge designed specifically for dc motor applications. The device provides forward, reverse, and brake modes of operation. A logic supply voltage of 5 V is internally derived from V_{CC} .

The TPIC0108B has an extremely low $r_{DS(on)}$, 280 m Ω typical, to minimize system power dissipation. The control inputs (IN1 and IN2) greatly simplify the microcontroller overhead requirement. The device has a low quiescent supply current of 20 μ A to suit a wide range of automotive and industrial battery-operated applications.

The TPIC0108B provides protection against over-voltage, over-current, over-temperature, and cross conduction faults. Fault diagnostics can be obtained by monitoring the STATUS1 and STATUS2 terminals and the two input control lines. STATUS1 is an open-drain output suitable for wired-or connection. STATUS2 is a push-pull output that provides a latched status output. Under-voltage protection ensures that the outputs, OUT1 and OUT2, will be disabled when $V_{\rm CC}$ is less than the under-voltage detection voltage $V_{\rm (UVCC)}$.

The TPIC0108B is designed using TI's LinBiCMOS™ process. LinBiCMOS allows the integration of low power CMOS structures, precision bipolar cells, and low impedance DMOS transistors.

The TPIC0108B is offered in a 20-pin thermally enhanced small-outline package (DWP) and is characterized for operation over the operating case temperature of –40°C to 125°C.

FUNCTION TABLE

IN1	IN2	OUT1	OUT2	MODE
0	0	Z	Z	Quiescent supply current mode
0	1	LS	HS	Motor turns clockwise
1	0	HS	LS	Motor turns counter clockwise
1	1	HS	HS	Brake, both HSDs turned on hard

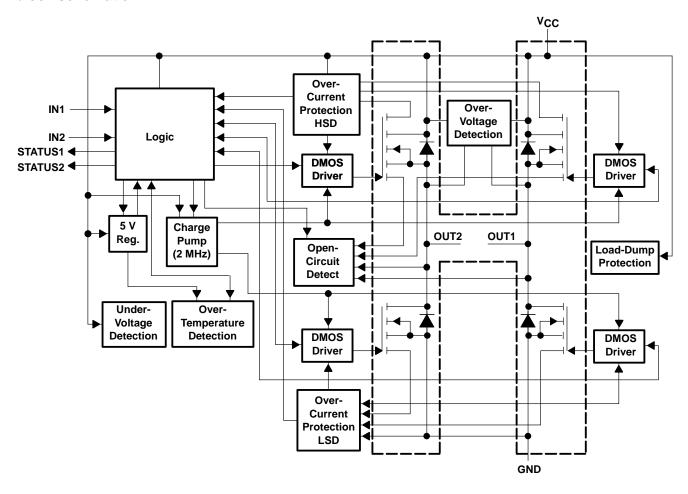


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block schematic



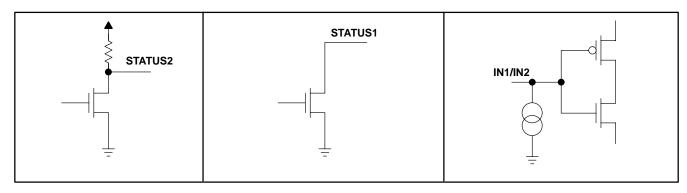
Terminal Functions

TERM	IINAL	1/0	DESCRIPTION
NAME	NO.	1/0	DESCRIPTION
GND	7, 9, 12, 14	I	Power ground
GNDS	1, 10, 11, 20	I	Substrate ground
IN1	3	I	Control input
IN2	8	I	Control input
OUT1	5, 6	0	Half-H output. DMOS output
OUT2	15, 16	0	Half-H output. DMOS output
STATUS1	13	0	Status output
STATUS2	18	0	Latched status output
VCC	2, 4, 17, 19	Ī	Supply voltage

NOTE: It is mandatory that all four ground terminals plus at least one substrate terminal are connected to the system ground. Use all V_{CC} and OUT terminals.



schematics of inputs and outputs



absolute maximum ratings over operating case temperature range (unless otherwise noted)[†]

Power supply voltage range, V _{CC}	0.3 V to 33 V
Logic input voltage range, V _{IN}	–0.3 V to 7 V
Load dump (for 400 ms; T _C = 25°C)	40 V
Status output voltage range, V _{O(status)}	–0.3 V to 7 V
Continuous power dissipation, T _C = 25°C	1.29 W
Storage temperature range, T _{stg}	–55°C to 150°C
Maximum junction temperature, T _J	150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

DISSIPATION RATING TABLE

T _A ≤ 25°C	DERATING FACTOR	T _A = 70°C	T _A = 125°C
POWER RATING	ABOVE T _A = 25°C	POWER RATING	POWER RATING
1.29 W	0.0104 W/°C	0.82 W	0.25 W

recommended operating conditions

	MIN	MAX	UNIT
Supply voltage, V _{CC}	6	18	V
Operating case temperature, T _C	-40	125	°C
Switching frequency, f _{PWM}		2	kHz

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electrical characteristics over recommended operating case temperature range and V_{CC} = 5 V to 6 V (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
		LSD	T _J = 25°C			550 mΩ	
 r=o,	Static drain-source on-resistance (per transistor)	LSD	T _J = 150°C			850	11122
rDS(on)	$I_{(BR)} = 1 A$	HSD	T _J = 25°C			600	mΩ
		T _J = 150°C			870	11122	
I(QCD)	Open circuit detection current			10	40	100	mA
V(UVCC(OFF))	Under voltage detection on V _{CC} , switch off voltage		See Note 1			5	V
V(UVCC(ON))	Under voltage detection on V _{CC} , switch on voltage		See Note 1			5.2	V
V _(STL)	STATUS low output voltage		$I_O = 100 \mu A$, See Note 1			0.8	V
V _(ST2H)	STATUS2 high output voltage		$I_O = 20 \mu A$, See Note 1	3		5.4	V
I(ST(OFF))	STATUS output leakage current		V _(ST) = 5 V, See Note 1			5	μΑ
V _{IL}	Low level logic input voltage			-0.3		0.5	V
VIH	High level logic input voltage			3.6		7	V
ΔVΙ	Hysteresis of input voltage			0.3			V
lн	High level logic input current	·	V _{IH} = 3.5 V	2	10	50	μΑ

NOTE 1: The device functions according to the function table for V_{CC} between $V_{(UVCC)}$ and 5 V (no parameters specified). STATUS outputs are not defined for V_{CC} less than $V_{(UVCC)}$.



electrical characteristics over recommended operating case temperature and supply voltage ranges (unless otherwise noted) (see Note 2)

	PARAMETER			TEST CONDITIONS			MAX	UNIT
		. 05	T _J = 25°C	V _{CC} = 6 V to 9 V			380	
			1J = 23 C	V _{CC} = 9 V to 18 V		280	340	-l mΩ l
(DO()		LSD	T 150°C	V _{CC} = 6 V to 9 V			620	
	Static drain-source on-resistance		T _J = 150°C	V _{CC} = 9 V to 18 V		400	560	
rDS(on)	(per transistor) I _{BR} = 1 A		T 25°C	$V_{CC} = 6 \text{ V to } 9 \text{ V}$			430	
		HSD	TJ = 25°C	V _{CC} = 9 V to 18 V		280	340	mΩ
		ПОО	T _{.1} = 150°C	V _{CC} = 6 V to 9 V			640	11122
			1J = 150°C	V _{CC} = 9 V to 18 V		400	560	
I(QB)	Quiescent battery current		T _J = 25°C V _{CC} = 13.2 V				20	μΑ
I(QCD)	Open circuit detection current				10	40	100	mA
T _{SDS}	Static thermal shutdown temperature		See Notes 3 and 4		140			°C
T _{SDD}	Dynamic thermal shutdown temperature		See Notes 3 and 5		160			°C
loo			$V_{CC} = 6 V \text{ to } 9 V$		4.8		7.5	Α
lcs	Current shutdown limit		V _{CC} = 9 V to 18 V		5		7.5	A
I _(CON)	Continuous bridge current		$T_J = 125$ °C, Operating lifetime 10,000 hours, (see Figure 1)				3	Α
V(OVCC)	Over voltage detection on V _{CC}				27		36	V
V(STL)	STATUS low output voltage		I _O = 100 μA				0.8	V
V(ST2H)	STATUS2 high output voltage		Ι _Ο = 20 μΑ		3.9		5.4	V
I(ST(OFF))) STATUS output leakage current		V _(ST) = 5 V				5	μΑ
V _{IL}	Low level logic input voltage				-0.3		0.8	V
VIH					3.6		7	V
ΔVΙ	Hysteresis of input voltage				0.3			V
lн	High level logic input current		V _{IH} = 3.5 V		2	10	50	μΑ

NOTES: 2. The device functions according to the function table for V_{CC} between 18 V and V_(OVCC), but only up to a maximum supply voltage of 33 V (no parameters specified). Exposure beyond 18 V for extended periods may affect device reliability.

switching characteristics over recommended operating case temperature and supply voltage ranges (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
	High-side driver turn-on time	V=0() (1 \ (ct 1 \			100	
tout(on)	Low-side driver turn-on time	$V_{DS(on)}$ <1 V at 1 A, V_{CC} = 13.2 V			100	μs
SR	Slew rate, low-to-high sinusoidal (δV/δt)	$V_{CC} = 13.2 \text{ V},$ $I_{C} = 1 \text{ A resistive load}$	1		6	V/µs
J SK	Slew rate, high-to-low sinusoidal ($\delta V/\delta t$)	V_{CC} = 13.2 V, I_O = 1 A resistive load	1		6	ν/μδ
td(QCD)	Under current spike duration to trigger open circuit detection	V _{CC} = 5 V to 18 V	1		10	ms
td(CS)	Delay time for over current shutdown		5	10	25	μs



^{3.} Exposure beyond absolute-maximum-rated condition of junction temperature may affect device reliability.

^{4.} No temperature gradient between DMOS transistor and temperature sensor.

^{5.} With temperature gradient between DMOS transistor and temperature sensor in a typical application (DMOS transistor as heat source).

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thermal resistance

	PARAMETER Junction-to-ambient thermal resistance Junction-to-case thermal resistance			UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance		97	°C/W
$R_{\theta JC}$	Junction-to-case thermal resistance		5	°C/W

PARAMETER MEASUREMENT INFORMATION

Maximum continuous bridge current versus time based on 50 FITs at 100,000 hours operating life (90% confidence model)

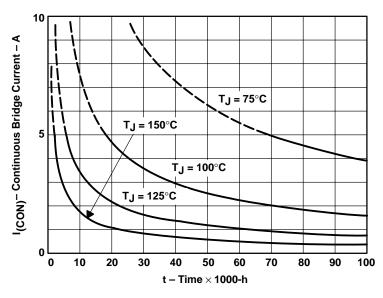


Figure 1. Electromigration Reliability Data

Example:

Average continuous bridge current, ICON	Average junction temperature, T _J	Operating lifetime of device based on electromigration
2 A	125°C	>20,000 h
3 A	125°C	>10,000 h



PARAMETER MEASUREMENT INFORMATION

operating wave forms

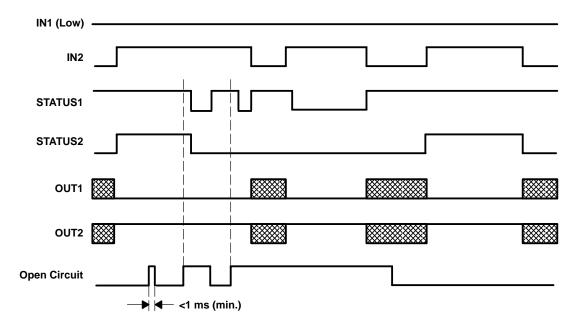


Figure 2. Open Circuit

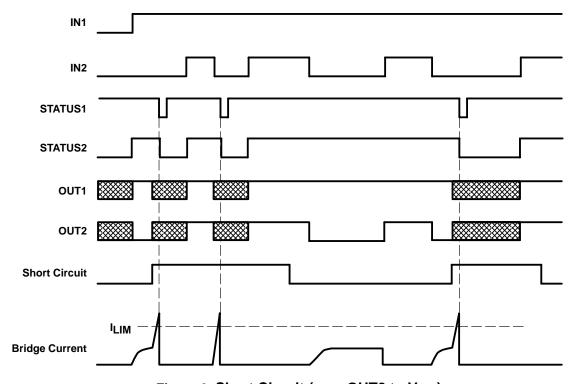


Figure 3. Short Circuit (e.g., OUT2 to V_{CC})



PARAMETER MEASUREMENT INFORMATION

operating wave forms (continued)

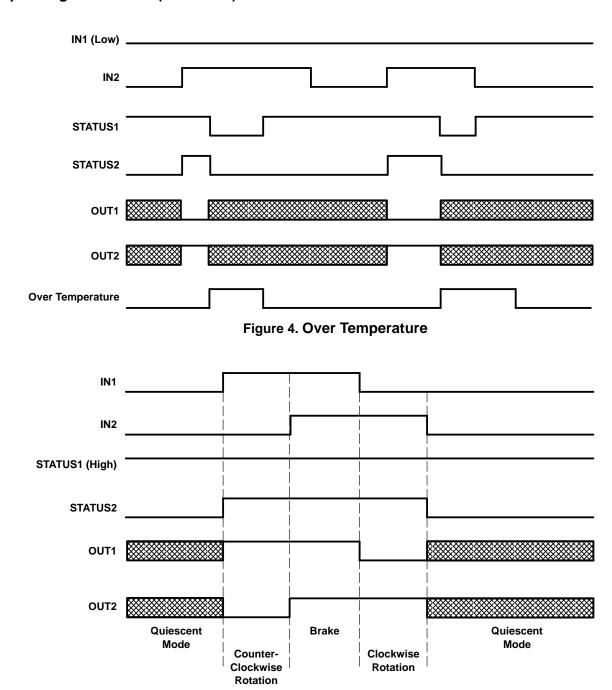


Figure 5. No Fault



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PRINCIPLES OF OPERATION

protective functions and diagnostics[†]

over current/short circuit‡

The TPIC0108B detects shorts to V_{CC} , ground, or across the load being driven, by comparing the V_{DS} voltage drop across the DMOS outputs against the threshold voltage. The DMOS outputs of the TPIC0108B will be disabled and the fault flags will be generated 10 μ s after an over-current or short-circuit fault is detected. This 10 μ s delay is long enough to serve as a de-glitch filter for high current transients, yet short enough to prevent damage to the DMOS outputs. The DMOS outputs remain latched off until either IN1 or IN2 input is toggled.

In cases where the outputs have a continuous short-to-ground or when enabled from quiescent mode with a short-to-ground already exists (current rise time faster than 0.5 A/ μ s in both instances), the over-current shutdown threshold will decrease to 3 A to reduce power dissipation. This reduction to 3 A is achieved since the DMOS outputs will not be fully enhanced when the over-current threshold is reached if the current rise time exceeds 0.5 A/ μ s. Over-current and/or short-circuit protection is provided up to V_{CC} = 16.5 V and a junction temperature of 90°C.

over temperature

The TPIC0108B disables all DMOS outputs and the fault flags will be set when T_J ≥140°C (min.). The DMOS outputs remain latched off until either IN1 or IN2 input is toggled.

under voltage

The TPIC0108B disables all DMOS outputs when $V_{CC} \le V_{(UVCC)}$. The outputs will be re-enabled when $V_{CC} \ge V_{(UVCC)}$. No fault flags are set when under-voltage lockout occurs.

over voltage

In order to protect the DMOS outputs from damage caused by excessive supply voltage, the TPIC0108B disables all outputs when $V_{CC} \ge V_{(OVCC)}$. Once $V_{CC} \le V_{(OVCC)}$, either IN1 or IN2 input must be toggled to re-enable the DMOS outputs.

cross conduction

Monitoring circuitry for each transistor detects whether the particular transistor is active to prevent the HSD or LSD of the corresponding half H-bridge from conducting.

open circuit

During operation, the bridge current is controlled continuously. If the bridge current is >10 mA (min.) for a period >1 ms (min.), the fault flags are set. However, the output transistors will not be disabled.

[‡] If a short circuit occurs (i.e., the over-current detection circuitry is activated) at a supply voltage higher than 16.5 V and a junction temperature higher than 90°C, damage to the device may occur.



[†] All limits mentioned are typical values unless otherwise noted.

PRINCIPLES OF OPERATION

DIAGNOSTICS TABLE (see Note 6)

FLAG	IN1	IN2	OUT1	OUT2	STATUS1 [†]	STATUS2
	0	0	Z LS	Z HS	1	0 [‡]
Normal operation	1	0	HS	LS	1	1
	1	1	HS	HS	1	1
Open circuit between OUT1 and OUT2	0 0 1	0 1 0	Z LS HS	Z HS LS	1 0 0	0 0 0
	1	1	HS	HS	1	1
Short circuit from OUT1 to OUT2 (see Notes 7 and 8)	0 1	1 0	X X	X X	0 0	0 0
Short circuit from OUT1 to GND (see Notes 7 and 8)	1 1	0 1	X X	X X	0 0	0 0
Short circuit from OUT2 to GND (see Notes 7 and 8)	0 1	1 1	X X	X X	0 0	0 0
Short circuit from OUT1 to V _{CC} (see Notes 7 and 8)	0	1	Х	Х	0	0
Short circuit from OUT2 to V _{CC} (see Notes 7 and 8)	1	0	Х	Х	0	0
	0	0	Z	Z Z	1	0‡
Over temperature (see Note 9)	1 1	0	Z Z Z	Z Z Z	0 0	0

[†]When wired with a pull-up resistor

SYMBOL VALUE

0 Logic low

1 Logic high

HS High-side MOSFET conducting LS Low-side MOSFET conducting Z No output transistors conducting

X Voltage level undefined

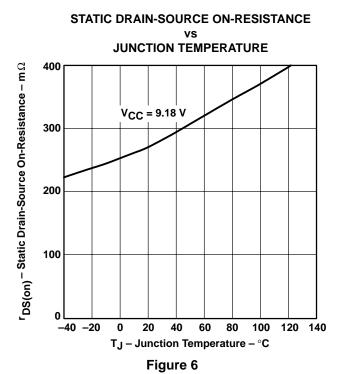
NOTES: 6. All input combinations not stated result in STATUS output = 1.

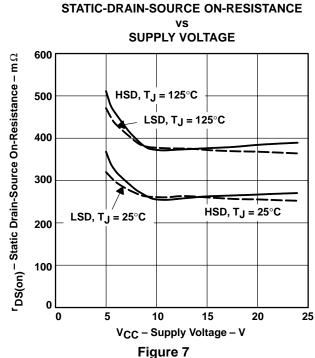
- 7. STATUS1 active for a minimum of 3 µs.
- 8. STATUS2 active until an input is toggled.
- 9. Quiescent current consumption can occur only when the temperature drops below the thermal switch-off temperature.

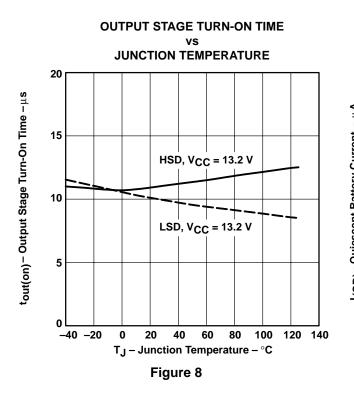


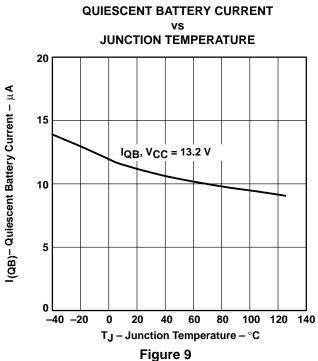
[‡] In quiescent mode, STATUS2 is pulled down to GND via an internal resistor.

TYPICAL CHARACTERISTICS

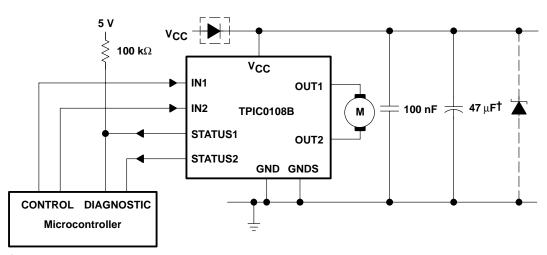








APPLICATION INFORMATION



[†] Necessary for isolating supply voltage or interruption (e.g., 47 μF).

NOTE: If a STATUS output is not connected to the appropriate microcontroller input, it shall remain unconnected.

recirculation current mode

When an inductive load (motor) is switched from one control mode to another, (i.e., forward to reverse) the TPIC0108B automatically enters a special recirculation current mode condition. This condition allows fast elimination of the recirculation currents caused by inductive switching. Once these currents have subsided to an acceptable level, the device automatically enters the requested state. This feature eliminates the need for either internally or externally connected free wheeling diodes and protects the TPIC0108B from damage due to high inductive voltage transients.

The recirculation current mode condition is triggered when the voltage at the HSD output voltage exceeds typically $V_{CC} + 0.7 \text{ V}$. In this condition, a diode inherent in the HSD structure turns on. Simultaneously internal control circuitry turns on the opposite HSD, thus providing a current path for the recirculating currents.

Using TPIC0108B in PWM operation brake mode shall be applied before going into quiescent mode.

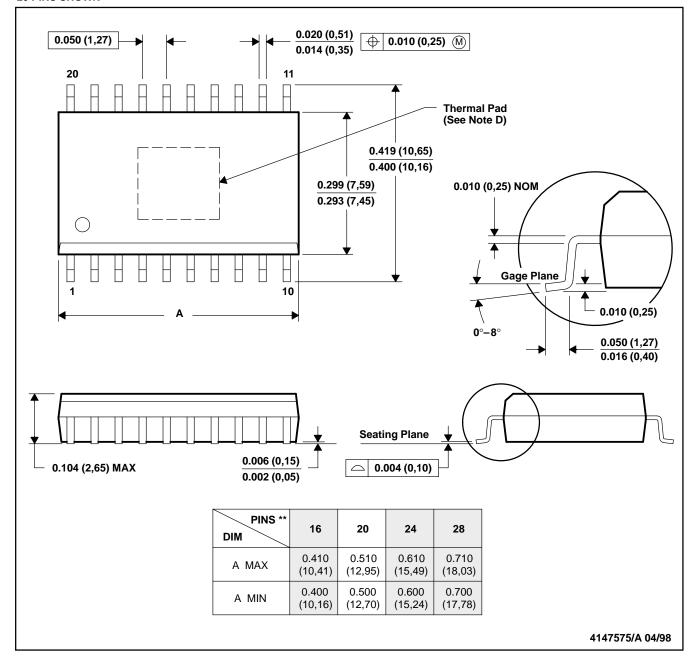


MECHANICAL DATA

DWP (R-PDSO-G**)

PowerPAD™ PLASTIC SMALL-OUTLINE PACKAGE

20 PINS SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. The package thermal performance may be enhanced by bonding the thermal pad to an external thermal plane. This pad is electrically and thermally connected to the backside of the die and possibly selected leads.

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